## In the United States Patent and Trademark Office

Serial No	
Appn. Filed :	
Applicant: Vladimir Mordekhay	
Appn. Title: A SYSTEM FOR PROCESSING	G SAMPLE PLATES WITH BUILT-IN
ELECTRONIC MEMORY FOR HIGH THRO	OUGHPUT SAMPLE PROCESSING
AND A PROCESSING METHOD	·
Examiner/GAU:	NOV. 4 /03
	Mailed: NOV. 5 / 03 At: San Carlos, CA
	At: Jun Color ; Cit
Information Disclos	ure Statement
Assistant Commissioner for Patents	
Washington, District of Columbia 20231	,
Sir:	

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the

references cited thereon. Following are comments on references pursuant to

Rule 98:

Systems for handling and analyzing sample plates with a plurality of samples for various analyses are known in the art. An example of a system for sample plates with liquid samples is a system for standard 384-position sample plates used by Cole Palmer, Inc. USA, for sample processing. Another example of the processing plate or filtering plate system is available from 3M Inc. Minnesota, USA (model #6060, 96-well Empore Filter Plate). In this system, the multiple samples are loaded and removed from the same sample filtering plate. On this 96-sample filtering or sample cleaning plate, each well is equipped with an absorbing material, and the bottom of the sample plate is open. Still another example of the prior-art device is a system for flat metal plates separated into individual regions (typically 96 or 384) that is used for matrix assisted laser ionization technique. The sample is deposited on the plate in a liquid form. After the sample dries, the plate is transferred into a mass spectrometer for the composition analysis. This device is also available commercially, for example, from MassTech Inc, MD, USA. Agilent technologies, Inc, USA, manufactures a DNA micro array chip and the optical scanning device (DNA Microarray Scanner, Model G2565BA) to analyze the DNA chip. In all the above cases, bar codes are used for tracking individual sample plates. The bar code method of tracking for the biochemical devices is limited to the amount of information that it can deliver. These records can be easily distributed between different computers, sample processing stations, and operators lab books making it difficult to insure the integrity of the records as well as their consistency. It may be also difficult to generate error-free final reports while performing high throughput analysis. With bar code labels, it is also difficult to change or modify label information dynamically during chip processing, e.g., when the sample plates are transferred from one station to another.

U.S. Patent Application No. 10/624,399 filed by the same applicant on July 21,

2003 discloses a system of sample-plate carriers, wherein samples are inserted into sample plate carriers, which are used for handling the sample plates with mechanical grippers of the sample plate handling mechanism. The aforementioned sample plate carriers are provided with built-in memory elements for inputting/outputting information relating to the samples, sample plates, or sample carriers. Such information may comprise description of the samples, description of the test procedure, description of all other events occurred with a specific sample plate or sample plate carrier, etc. However, in those applications that involve creation of sample banks required for generation of large-volume data bases, the use of intermediate elements, such as sample plate carriers, may become inconvenient and economically unjustifiable. This is because the carriers dictate the use of large storage cassettes. Furthermore, since the information about specific sample plates is stored in the memory elements, which are physically separated from the sample plates. Therefore, the information about the samples and sample plates, e.g., process history, can be lost. Furthermore, the sample carriers themselves are relatively complicated devices that occupy an addition space and increase the cost of the operations and of sample plate handling system as a whole.

Thus, none of the references mentioned above discloses, as claimed in my Claim 1 with dependant Claims 2-20, a sample plate processing system that in its simplest version consists of a sample deposition station with a data input/output unit and a sample processing station for processing and/or analyzing samples carried by the sample plates, the sample processing station being equipped with data input/output unit and interacting with an electronic memory permanently built into each sample plate. Furthermore, none of the references discloses, as a claimed in my independent Claim 21 with dependent Claims 22-24, a method for processing a plurality of samples supported by sample plates with built-in electronic memory wherein the samples are loaded into sample plates, the

built-in electronic memory is loaded with a required data simultaneously with sample loading or in a separate operation, and the samples are processed or analyzed.

Respectfully, Vladimir Morekuhay

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STATEMENT BY APPLICANT	First Named Inventor			
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	١.	Cule Palmer Inc. USA Sample plate with 384-positions.	
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	2.	3M Inc., Minnesota, USA. (model #6060 96-well Empore Filter Plate)	
		Mass Tech Inc., MD, USA. Sample plates for Mass Spectrometry for	
	_	for Mass Spectrometry for	_
		Agilent Technologies, Inc, USA	
	4.	DNA MICROARRAY SCANNER, Mod. G2565BA	
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	6	Combined Raman and FTIR Microspectro- Scopy (Labramir)	

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